MOTOROLA

Military 54LS375

4-Bit Bistable Latch

ELECTRICALLY TESTED PER:
MIL-M-38510/31604

The 54LS375 is a 4-bit D-Type Latch for use as temporary storage for binary information between processing limits and input/output or indicator units. When the Enable (E) is HIGH, information present at the D input will be transferred to the Q output and, if E is HIGH, the Q output will follow the input. When E goes LOW, the information present at the D input prior to its setup time will be retained at the Q outputs.

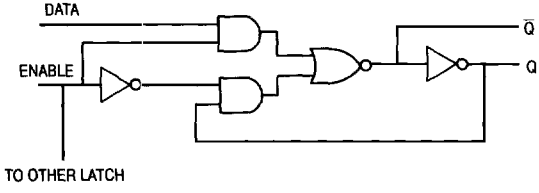
AVAILABLE AS:

1) JAN: JM38510/31604BXA
2) SMD: N/A
3) 883: 54LS375/BXAJC

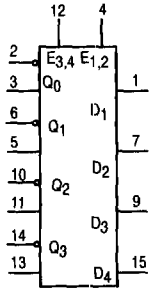
X = CASE OUTLINE AS FOLLOWS:
PACKAGE: CERDIP: E
CERFLAT: F
LCC: 2

THE LETTER "M" APPEARS BEFORE THE / ON LCC.

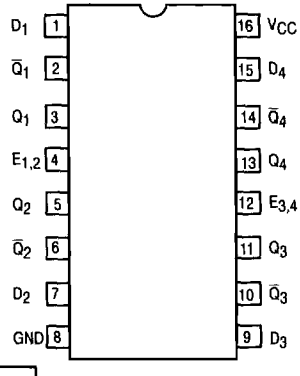
LOGIC DIAGRAM



LOGIC SYMBOL



CONNECTION DIAGRAM



PIN ASSIGNMENTS

FUNCT.	DIL 620-09	FLATS 650-05	LCC 756A-02	BURN-IN (COND. A)
D_1	1	1	2	V_{CC}
$\bar{Q}_1$	2	2	3	OPEN
Q_1	3	3	4	V_{CC}
E_{1-2}	4	4	5	V_{CC}
Q_2	5	5	7	V_{CC}
$\bar{Q}_2$	6	6	8	OPEN
D_2	7	7	9	V_{CC}
GND	8	8	10	GND
D_3	9	9	12	V_{CC}
$\bar{Q}_3$	10	10	13	OPEN
Q_3	11	11	14	V_{CC}
E_{3-4}	12	12	15	V_{CC}
Q_4	13	13	17	V_{CC}
$\bar{Q}_4$	14	14	18	OPEN
D_4	15	15	19	V_{CC}
V_{CC}	16	16	20	V_{CC}

BURN-IN CONDITIONS:
V_{CC} = 5.0 V MIN/6.0 V MAX

Pin Names		Loading (Note a) HIGH	LOW
D_1-D_2	Data Inputs	0.5 U.L.	0.25 U.L.
E_0-E_1	Enable Input Latches 0, 1	2.0 U.L.	1.0 U.L.
E_2-E_3	Enable Input Latches 2, 3	2.0 U.L.	1.0 U.L.
Q_1-Q_4	Latch Outputs (Note b)	10 U.L.	5(2.5) U.L.
$\bar{Q}_1$-$\bar{Q}_4$	Complementary Latch Outputs (Note b)	10 U.L.	5(2.5) U.L.

NOTES:
a. One TTL Unit Load (U.L.) = 40 µA HIGH/1.6 mA LOW.
b. The Output LOW drive factor is 2.5 U.L. for Military (54) and 5 U.L. for commercial (74) Temperature Ranges.

TRUTH TABLE (Each Latch)

t_n	$t_n + 1$
D	Q
H	H
L	L

t_n = Bit time before enable negative-going transition
$t_n + 1$ = Bit time after enable negative-going transition.

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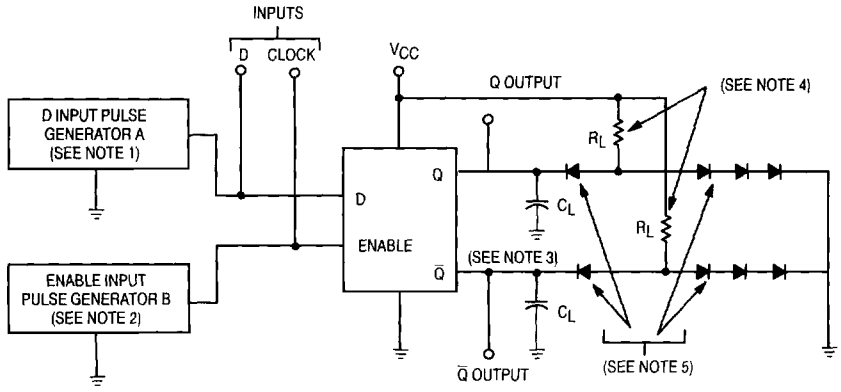
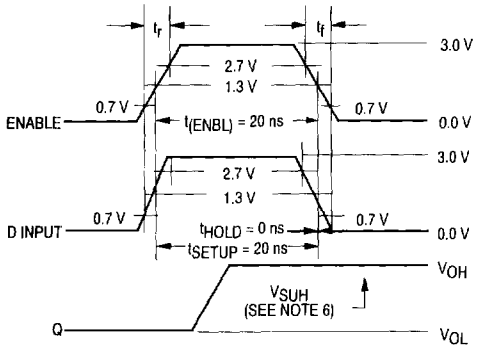
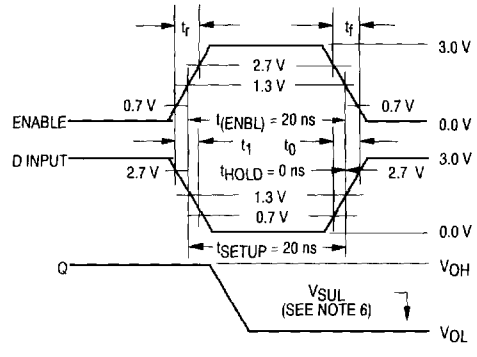
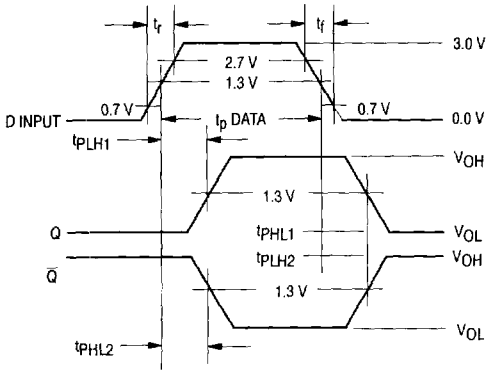
SWITCHING TEST CIRCUIT

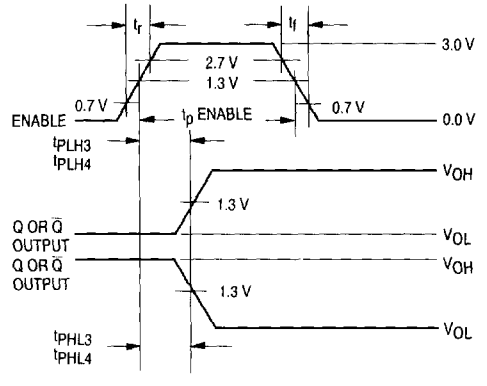


SETUP AND HOLD WAVEFORMS









REFERENCE NOTES ON PAGE 5-394

Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)
	Static Parameters:	+ 25°C		+ 125°C		− 55°C			
		Subgroup 1		Subgroup 2		Subgroup 3			
		Min	Max	Min	Max	Min	Max		
V_{OH}	Logical "1" Output Voltage	2.5		2.5		2.5		V	V_{CC} = 4.5 V, I_{OH} = − 0.4 mA, V_{IH} = 2.0 V or 0.7 V per truth table, Enable = (See Note 7).
V_{OL}	Logical "0" Output Voltage		0.4		0.4		0.4	V	V_{CC} = 4.5 V, I_{OL} = 4.0 mA, V_{IL} = 0.7 V or 2.0 V per truth table, Enable = (See Note 7).
V_{IC}	Input Clamping Voltage		− 1.5					V	V_{CC} = 4.5 V, I_{IN} = − 18 mA, other inputs are open.
I_{IH}	Logical "1" Input Current (D inputs)		20		20		20	µA	V_{CC} = 5.5 V, V_{IH} = 2.7 V, other input is open.
I_{IHH}	Logical "1" Input Current (E_n inputs)		80		80		80	µA	V_{CC} = 5.5 V, V_{IH} = GND, $V_{IN}(E_n)$ = 2.7 V.
I_{IH}	Logical "1" Input Current (D inputs)		100		100		100	µA	V_{CC} = 5.5 V, V_{IH} = 5.5 V, $V_{IN}(E_n)$ = GND.
I_{IHH}	Logical "1" Input Current (E_n inputs)		400		400		400	µA	V_{CC} = 5.5 V, V_{IH} = GND, $V_{IN}(E_n)$ = 5.5 V.
I_{IL}	Logical "0" Input Current (D inputs)	− 0.16	− 0.4	− 0.16	− 0.4	− 0.16	− 0.4	mA	V_{CC} = 5.5 V, V_{IL} = 0.4 V, $V_{IN}(E_n)$ = 4.5 V.
I_{IL}	Logical "0" Input Current (E_n inputs)	− 0.64	− 1.6	− 0.64	− 1.6	− 0.64	− 1.6	mA	V_{CC} = 5.5 V, $V_{IN}(E_n)$ = 0.4 V, other input = 4.5 V.
I_{OS}	Output Short Circuit Current	− 15	− 100	− 15	− 100	−15	− 100	mA	V_{CC} = 5.5 V, $V_{IN}(E_n)$ = 4.5 V, other input = GND.
I_{CC}	Power Supply Current		12		12		12	mA	V_{CC} = 5.5 V, V_{IN} = 0 V (all inputs).
V_{IH}	Logical "1" Input Voltage	2.0		2.0		2.0		V	V_{CC} = 4.5 V.
V_{IL}	Logical "0" Input Voltage		0.7		0.7		0.7	V	V_{CC} = 4.5 V.
	Functional Tests	Subgroup 7		Subgroup 8A		Subgroup 8B			per Truth Table with V_{CC} = 5.0 V, V_{INL} = 0.4 V, and V_{INH} = 2.5 V.

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Symbol	Parameter	Limits						Unit	Test Condition (Unless Otherwise Specified)
	Switching Parameters:	+ 25°C		+ 125°C		− 55°C			
		Subgroup 9		Subgroup 10		Subgroup 11			
		Min	Max	Min	Max	Min	Max		
t_{PHL1} t_{PHL1}	Propagation Delay Data-Output Data to Q	3.0 —	22 17	3.0 —	29 24	3.0 —	29 24	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%. V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
t_{PLH1} t_{PLH1}	Propagation Delay Data-Output Data to Q	3.0 —	32 27	3.0 —	42 37	3.0 —	42 37	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%. V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
t_{PHL2} t_{PHL2}	Propagation Delay Data-Output Data to $\overline{Q}$	3.0 —	20 15	3.0 —	26 21	3.0 —	26 21	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%. V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
t_{PLH2} t_{PLH2}	Propagation Delay Data-Output Data to $\overline{Q}$	3.0 —	25 20	3.0 —	32 27	3.0 —	32 27	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%. V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
t_{PHL3} t_{PHL3}	Propagation Delay Data-Output Enable to Q	3.0 —	30 25	3.0 —	39 34	3.0 —	39 34	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%. V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
t_{PLH3} t_{PLH3}	Propagation Delay Data-Output Enable to Q	3.0 —	32 27	3.0 —	42 37	3.0 —	42 37	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%, V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
t_{PHL4} t_{PHL4}	Propagation Delay Data-Output Enable to $\overline{Q}$	3.0 —	20 15	3.0 —	26 21	3.0 —	26 21	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%. V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
t_{PLH4} t_{PLH4}	Propagation Delay Data-Output Enable to $\overline{Q}$	3.0 —	35 30	3.0 —	46 41	3.0 —	46 41	ns	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%. V_{CC} = 5.0 V, C_L = 15 pF, R_L = 2.0 kΩ ± 5.0%.
V_{SUH}	Logical "1" Setup Voltage	2.5		2.5		2.5		V	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%.
V_{SUL}	Logical "0" Setup Voltage		0.4		0.4		0.4	V	V_{CC} = 5.0 V, C_L = 50 pF, R_L = 2.0 kΩ ± 5.0%.

NOTES:

1. The D input pulse generator has the following characteristics: V_{GEN} = 3.0 V, $t_r \leq 15$ ns, $t_f \leq 6.0$ ns, t_p = 30 ns and Z_{OUT} = 50 Ω except when measuring V_{SETUP}.
2. The enable pulse generator is identical to the D input pulse generator.
3. C_L = 50 pF ± 10%, which includes probe and jig capacitance.
4. R_L = 2.0 kΩ ± 5%.
5. All diodes are 1N3064 or equivalent
6. V_{SETUP} is to be measured 500 ns minimum after input transition to assure that the device has latched with minimum setup and maximum hold conditions applied to inputs.
7. Apply 0.0 V/3.0 V – 5.0 V/0.0 V momentary pulse 500 ns minimum prior to making test
8. For all t_{PLH} and V_{SUH} tests, preset output into the ZERO states prior to making test.
9. For all t_{PHL} and V_{SUL} tests, preset output into ONE states prior to making test.
10. The limits specified for C_L = 15 pF are guaranteed but not tested.